

WHAT IS CLAIMED IS:

1. A device for cleaning probe pins of a probe head assembly, comprising:
 - 5 a first holding plate for securing said probe head assembly;
 - a cleaning cartridge having a chamber and a cleaning solution and an absorbent pad located within said chamber, said absorbent pad being saturated with said cleaning solution and preventing leakage of said cleaning solution out of said chamber; and
 - a second holding plate for securing and aligning said cleaning cartridge in
 - 10 proximity to said probe head assembly;wherein said first holding plate is positioned relative to said second holding plate such that said probe pins contact said absorbent pad so that said cleaning solution acts upon said probe pins.
- 15 2. The cleaning device as set forth in claim 1 wherein said first holding plate is affixed to said second holding plate so as to be rotated into alignment with said second holding plate.
- 20 3. The cleaning device as set forth in claim 1 wherein said first holding plate, said second holding plate and said cleaning cartridge are comprised of a chemically inert material.

4. The cleaning device as set forth in claim 3 wherein said chemically inert material is polyvinylchloride.

5. The cleaning device as set forth in claim 1 wherein said cleaning cartridge
5 includes a removable and reusable cover.

6. A method for cleaning probe tips of a probe head assembly, the method comprising the steps of:

providing a cleaning cartridge having a chamber including a cleaning solution and
10 an absorbent pad, the cleaning cartridge dimensioned for controlling a depth by which probe pin penetrate into the chamber;

providing a holding fixture for the probe head assembly;

aligning the holding fixture in proximity to the cleaning cartridge such that the probe pins contact the absorbent pad and cleaning solution, wherein the cleaning solution
15 acts upon the probe pin tips and the absorbent pad captures debris removed from the tips of the probe pins.